

WHAT IS CLAIMED IS:

1. A probe comprising:

an almost rectilinear contact part which can come in contact with an electrode of an object to be measured almost perpendicularly; and

a base end continued to the contact part,

characterized in that said contact part further comprises a base part and an almost rectilinear junction part which is formed of a material having a thermal expansion coefficient different from that of the base part and provided integrally and longitudinally along a widthwise end of the base part,

and in that said contact part is deformed in a direction almost perpendicular to the longitudinal direction of said base part due to respective thermal expansion of said base part and said junction part at 85 to 125°C.

2. A probe comprising:

an almost rectilinear contact part which can come in contact with an electrode of an object to be measured almost perpendicularly; and

a base end continued to the contact part,

characterized in that said contact part further comprises a base part and a junction part which is integrally provided at a widthwise end of said base part,

in that said junction part is formed of a shape memory alloy which can be expanded or contracted in a longitudinal direction of said base part at 80 to 90°C,

and in that said contact part is deformed in a direction almost perpendicular to the longitudinal direction of said base part due to deformation of said junction part.